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L2	16511	(wavelet or subband$2 or sub-band$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 14:10
L3	5	1 same 2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 11:28
L4	3	1 with 2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 11:36
L5	10701	382/240,243,236,239,238,244, 250-253,276,162,166-167;358/426. 02-426.11;348/400.1-421.1;341/51, 79;375/240.1,240.03,240.11-240. 13,240.16,240.18-240.19,240.24. ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 11:46
L6	344	5 and inter with intra with(select$4 or adaptiv$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 11:46
L7	1596	5 and(wavelet or subband$2 or sub-band$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 11:47
L8	35	6 and 7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 13:15
L9	14	8 and scen$2 near3 chang$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:49

L10	18037	(wavelet or subband$2 or sub-band$2 or block-based or segment-based)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:51
L11	260	10 and (pyramid$5 near3 (cod$3 or encod$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 14:26
L12	50	11 and(down adj1 sampl$3 or down-sampl$3 or downsampl$3) and (up-sampl$3 or upsampl$3 or up adj1 sampl$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:50
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L14	848	10 and pyramid$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:51
L15	94	14 and(down adj1 sampl$3 or down-sampl$3 or downsampl$3) and (up-sampl$3 or upsampl$3 or up adj1 sampl$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:02
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L17	2	12 and scen$2 near3 chang$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:03
L18	2	"6477279".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:02
L19	0	18 and scen$2 near3 chang$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:52

L20	0	18 and scen$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:03
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L22	11	21 and ((inter with intra with(select$4 or adaptiv$4)) or (intra-inter near3 (decision or select$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:50
L23	0	22 and(down adj1 sampl$3 or down-sampl$3 or downsampl$3) and (up-sampl$3 or upsampl$3 or up adj1 sampl$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:50
L24	0	22 and pyramid$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:51
L25	1	22 and(wavelet or subband$2 or sub-band$2 or block-based or segment-based)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 15:52
L26	1	22 and scen$2 near3 chang$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 16:03
L27	0	"57706220".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 16:03
L28	2	"5706220".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 17:35
L29	31	prakash-adityo.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/26 17:35

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1 **A method of de-interlacing with motion compensated interpolation**
Sugiyama, K.; Nakamura, H.;
Consumer Electronics, IEEE Transactions on , Volume: 45 , Issue: 3 , Aug. 19
Pages:611 - 616

[Abstract]   [PDF Full-Text (360 KB)]   **IEEE JNL**

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